				A	75 Rec'd	PCT/PTA <sup>n</sup>	28 SEP DO		
Form PTO-1449 U.S. Department of Commerce (Modified) Patent and Trademark Office				ce Attorney's Docket I	Attorney's Docket No. 28953.2004		Application No.		
Information Disclosure Statement by Applicant				Applicant	Makoto IW	Al et al	4846		
(Use several sheets if necessary)					08/2006				
(37 CFR §1.98(b))				Herewith	Herewith 1792				
U.S. Patent Documents									
Examiner	Desig.	Patent		i			Filing Date		
Initial	ID	Number	Issue Date	Patentee	Class	Subclass	If Appropriate		
/F.H./	AA	6,949,140	9/2005	Sarayama et al	117	81			
/F.H./	AB	6,398,867	6/2002	D'Evelyn et al	117	11			

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publn.	Country or			Transla	ation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
/F.H./	AC	2002-293696	10/2002	Japan			Abstract	
/F.H./	AD	2003-292400	10/2003	Japan	-		Abstract	
/F.H./	AE	2003-511326	3/2003	Japan			Х	
/F.H./	AF	2005-8444	1/2005	Japan			Abstract	
/F.H./	AG	WO2004/013385	6/2003	WIPO			Abstract	
/F.H./	AH	WO01/024921	9/2000	WIPO				
	AI							
	AJ							
	AK							
	AL							
	AM			İ				
	AN							
	AO			· ·				

Other Documents (include Author, Title, Date, and Place of Publication)					
Examiner	Desig.				
Initial	ID	Document			
/F.H./	AP	Kawamura, F. et al, "Growth of a Large GaN Single Crystal Using the Liquid Phase Epitaxy (LPE) Technique," Jpn. J. Appl. Phys., Vol. 42 (2003), pp. L4-L6			
	AQ				
	AR	·			
	AS				
	AT				

Examiner Signature	Date Considered			
/Felisa Hiteshew/	04/11/2008			
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.				